



SMC-02-1259

December 15, 2003

To: Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/671,293 09/25/03 |

Chung-Hui Chen

SELF-LEAKAGE DETECTION CIRCUIT OF
DECOUPLING CAPACITOR IN MOS
TECHNOLOGY

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on December 19, 2003.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 12/19/03

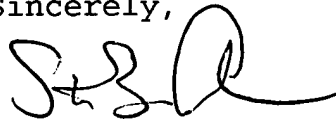
The following two U.S. Patents teach a circuit to detect a defective decoupling capacitor during a power-up test:

- 1) U.S. Patent 5,506,457 to Krauter et al., "Electronic Switch for Decoupling Capacitor."
- 2) U.S. Patent 6,307,250 to Krauter et al., "Electronic Switch for Decoupling Capacitor."

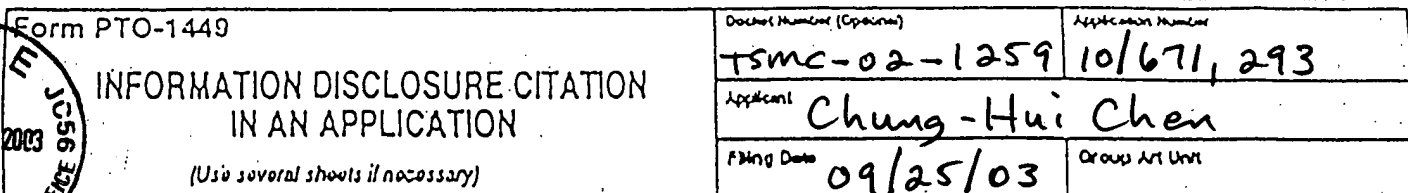
U.S. Patent 5,789,964 to Voldman, "Decoupling Capacitor Network for Off-State Operation," discloses a method to detect a defective decoupling capacitor during power-up and to switch in a capacitor during an ESD event.

U.S. Patent Application Publication US 2002/0081832 A1 to Bernstein et al., "Intralevel Decoupling Capacitor, Method of Manufacture and Testing Circuit of the Same," describes a circuit to test decoupling capacitors in an integrated circuit device.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a stylized flourish extending to the right.

Stephen B. Ackerman,
Reg. No. 37761

[illegible]

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

		U.S. Patent App. Publication US 2002/0081832 A1 to Bernstein et al., Pub. Date 6/27/02, "Intra level Decoupling Capacitor, Method of Manufacture and Testing Circuit of the Same".

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.